

Application/Control No.	Applicant(s)/Patent under Reexamination NAKAYAMA ET AL.	
10/770,125		
Examiner	Art Unit	
David J. Walczak	3751	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARC (INCLUDING SEA	H NOTES ARCH STRATEG	Υ)
	DATE	EXMR
updated prior search	5/16/2005	DW